

# ISO/TS 23302:2021-11 (E)

## Nanotechnologies - Requirements and recommendations for the identification of measurands that characterise nano-objects and materials that contain them

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| <b>Contents</b> |  | <b>Page</b> |
|-----------------|--|-------------|
| Foreword        |  | vii         |
| Introduction    |  | viii        |
| <b>1</b>        | <b>Scope</b>   | <b>1</b>    |
| <b>2</b>        | <b>Normative references</b>  | <b>1</b>    |
| <b>3</b>        | <b>Terms and definitions</b>   | <b>1</b>    |
| 3.1             | General core terms   | 1           |
| 3.2             | Measurand related terms  | 3           |
| <b>4</b>        | <b>Abbreviated terms</b>   | <b>6</b>    |
| <b>5</b>        | <b>Approaches to identify measurands to characterize nano-objects and their agglomerates and aggregates, and materials containing nano-objects</b> | <b>9</b>    |
| 5.1             | Procedure  | 9           |
| 5.2             | Types of measurands  | 10          |
| 5.3             | State of nano-objects  | 10          |
| <b>6</b>        | <b>Measurands related to size and shape measurement of nano-objects and their agglomerates and aggregates</b>                                      | <b>11</b>   |
| 6.1             | General  | 11          |
| 6.2             | Measurands related to size and shape measurement   | 11          |
| 6.2.1           | Overview   | 11          |
| 6.2.2           | General relevant standards   | 12          |
| 6.3             | Measurands related to size and shape measurement in aerosols   | 12          |
| 6.3.1           | Overview   | 12          |
| 6.3.2           | General relevant standards   | 13          |
| 6.3.3           | Electrical low-pressure impaction  | 13          |
| 6.3.4           | Cascade impactors  | 14          |
| 6.3.5           | Differential mobility analysing system   | 14          |
| 6.3.6           | Relevant standards   | 15          |
| 6.3.7           | Optical particle counter   | 15          |
| 6.3.8           | Relevant standards   | 15          |
| 6.3.9           | Aerodynamic particle sizing  | 15          |
| 6.3.10          | TEM combined with TEM grid samplers  | 15          |
| 6.3.11          | Relevant standards   | 16          |
| 6.3.12          | Scanning electron microscopy   | 16          |
| 6.3.13          | Relevant standards   | 17          |
| 6.4             | Measurands related to size and shape measurement in powders  | 17          |
| 6.4.1           | Overview   | 17          |
| 6.4.2           | Relevant standards   | 17          |
| 6.4.3           | Scanning electron microscopy   | 18          |
| 6.4.4           | Relevant standards   | 18          |
| 6.4.5           | Gas adsorption, the BET method   | 18          |
| 6.4.6           | Relevant standard  | 18          |
| 6.4.7           | Laser diffraction  | 18          |
| 6.4.8           | Relevant standard  | 19          |
| 6.4.9           | X-ray diffraction  | 19          |
| 6.4.10          | Relevant standards   | 19          |
| 6.4.11          | Raman spectroscopy   | 19          |
| 6.5             | Measurands related to size and shape measurements of nano-objects in liquid dispersions  | 20          |
| 6.5.1           | Overview   | 20          |
| 6.5.2           | Centrifugal liquid sedimentation   | 21          |
| 6.5.3           | Relevant standards   | 21          |
| 6.5.4           | Dynamic light scattering   | 21          |
| 6.5.5           | Relevant standards   | 22          |

|          |   |           |
|----------|---|-----------|
| 6.5.6    | Laser diffraction   | 22        |
| 6.5.7    | Relevant standard   | 22        |
| 6.5.8    | Small angle X-ray scattering  | 22        |
| 6.5.9    | Relevant standard   | 22        |
| 6.5.10   | Particle tracking analysis  | 22        |
| 6.5.11   | Relevant standards  | 23        |
| 6.5.12   | Electron microscopy   | 23        |
| 6.5.13   | Field flow fractionation  | 23        |
| 6.5.14   | Relevant standard   | 24        |
| 6.5.15   | Single particle ICP-MS  | 24        |
| 6.5.16   | Relevant standard   | 25        |
| 6.6      | Measurands related to size and shape measurement on surfaces (microscopy techniques)                  | 25        |
| 6.6.1    | Overview  | 25        |
| 6.6.2    | Scanning electron microscopy  | 25        |
| 6.6.3    | Atomic force microscopy   | 25        |
| 6.6.4    | Relevant standards  | 26        |
| <b>7</b> | <b>Measurands related to chemical analysis of nano-objects and their agglomerates and aggregates</b>  | <b>26</b> |
| 7.1      | General   | 26        |
| 7.2      | Measurands related to surface chemical analysis of nano-objects and their agglomerates and aggregates | 27        |
| 7.2.1    | Measurands  | 27        |
| 7.2.2    | Auger electron spectroscopy   | 28        |
| 7.2.3    | Relevant standards  | 28        |
| 7.2.4    | Electron energy loss spectroscopy   | 28        |
| 7.2.5    | Relevant standard   | 28        |
| 7.2.6    | Secondary ion mass spectroscopy   | 28        |
| 7.2.7    | Relevant standards  | 29        |
| 7.2.8    | X-ray fluorescence spectroscopy   | 29        |
| 7.2.9    | Relevant standards  | 30        |
| 7.2.10   | X-ray diffraction   | 30        |
| 7.2.11   | Relevant standard   | 30        |
| 7.2.12   | X-ray photoelectron spectroscopy  | 30        |
| 7.2.13   | Relevant standards  | 31        |
| 7.2.14   | Energy dispersive X-ray spectroscopy  | 31        |
| 7.2.15   | Low energy ion scattering   | 31        |
| 7.3      | Measurands related to the chemical analysis of nano-objects as bulk samples                           | 31        |
| 7.3.1    | Measurands  | 31        |
| 7.3.2    | Fourier transform infrared spectroscopy   | 32        |
| 7.3.3    | Relevant standards  | 33        |
| 7.3.4    | Thermal analysis with evolved gas analyser plus FTIR or QMS   | 33        |
| 7.3.5    | Relevant standards  | 34        |
| 7.3.6    | Ultraviolet-visible spectroscopy  | 34        |
| 7.3.7    | Relevant standards  | 34        |
| 7.3.8    | Raman spectroscopy  | 34        |
| 7.3.9    | Inductively coupled plasma techniques   | 34        |
| 7.3.10   | Relevant standards  | 34        |
| 7.3.11   | Contact angle   | 35        |
| <b>8</b> | <b>Measurands related to mass and density</b>   | <b>35</b> |
| 8.1      | General   | 35        |
| 8.2      | Aerosols  | 35        |
| 8.2.1    | Measurands  | 35        |
| 8.2.2    | Relevant standards  | 35        |
| 8.2.3    | Aerosol particle mass analyser  | 36        |
| 8.2.4    | Time of flight mass spectrometry  | 36        |
| 8.3      | Powders   | 36        |

|           |        |  |           |
|-----------|--------|--|-----------|
|           | 8.3.1  | Measurands.....  | 36        |
|           | 8.3.2  | Pycnometry.....  | 36        |
|           | 8.3.3  | Relevant standards.....  | 36        |
| 8.4       |        | Liquid dispersions.....  | 37        |
|           | 8.4.1  | Measurands.....  | 37        |
|           | 8.4.2  | Relevant standards.....  | 37        |
|           | 8.4.3  | Centrifugal liquid sedimentation (isopycnic method).....                             | 37        |
|           | 8.4.4  | Static light scattering.....   | 37        |
|           | 8.4.5  | Resonant mass measurement.....   | 38        |
| <b>9</b>  |        | <b>Measurands related to charge — Liquid dispersions.....</b>                        | <b>38</b> |
|           | 9.1    | Measurands.....  | 38        |
|           | 9.2    | Relevant standards.....  | 38        |
|           | 9.3    | Electrophoretic light scattering.....  | 38        |
|           | 9.4    | Electroacoustic phenomena measurements.....  | 39        |
| <b>10</b> |        | <b>Measurands related to crystallinity.....</b>                                      | <b>39</b> |
|           | 10.1   | Measurands.....  | 39        |
|           | 10.2   | Small-angle/wide-angle X-ray scattering.....   | 40        |
|           | 10.3   | X-ray diffraction.....   | 40        |
|           | 10.4   | High-resolution transmission electron microscopy.....                                | 41        |
|           | 10.5   | Electron backscattered diffraction.....  | 41        |
|           | 10.6   | Neutron diffraction.....   | 41        |
|           | 10.7   | Reflection high-energy electron diffraction and low-energy electron diffraction..... | 41        |
|           | 10.8   | Differential scanning calorimetry.....   | 41        |
|           | 10.9   | Relevant standards.....  | 42        |
|           | 10.10  | Solid state nuclear magnetic resonance crystallography.....                          | 42        |
|           | 10.11  | Raman crystallography.....   | 42        |
|           | 10.12  | Relevant standards.....  | 42        |
| <b>11</b> |        | <b>Optical properties measurands.....</b>  | <b>42</b> |
|           | 11.1   | General.....   | 42        |
|           | 11.2   | Measurands.....  | 43        |
|           | 11.3   | Spectroscopy techniques.....   | 43        |
|           | 11.4   | Relevant standards.....  | 44        |
| <b>12</b> |        | <b>Electrical and electronic measurands.....</b>                                     | <b>44</b> |
|           | 12.1   | Measurands.....  | 44        |
|           | 12.2   | Techniques.....  | 45        |
|           | 12.2.1 | 2- or 4-point conductance measurements.....  | 45        |
|           | 12.2.2 | Angle-resolved ultraviolet photoemission spectroscopy.....                           | 45        |
|           | 12.2.3 | Scanning tunnelling microscopy.....  | 45        |
|           | 12.2.4 | Conductive atomic force microscopy.....  | 45        |
|           | 12.2.5 | Piezoforce microscopy.....   | 46        |
| <b>13</b> |        | <b>Magnetic measurands.....</b>  | <b>46</b> |
|           | 13.1   | General.....   | 46        |
|           | 13.2   | Measurands.....  | 46        |
|           | 13.3   | Techniques.....  | 47        |
|           | 13.3.1 | Superconducting quantum interference device.....                                     | 47        |
|           | 13.3.2 | Vibrating sample magnetometer.....   | 48        |
|           | 13.3.3 | Mössbauer spectroscopy.....  | 48        |
|           | 13.3.4 | Electron paramagnetic resonance spectroscopy.....                                    | 48        |
|           | 13.3.5 | Magneto-optical Kerr-effect.....   | 48        |
|           | 13.3.6 | Magnetic force microscopy.....   | 48        |
|           | 13.3.7 | Scanning Hall effect microscopy.....   | 48        |
|           | 13.3.8 | Spin-polarized scanning tunnelling microscopy.....                                   | 49        |
|           | 13.3.9 | Relevant standards.....  | 49        |
| <b>14</b> |        | <b>Thermal measurands.....</b>   | <b>49</b> |
|           | 14.1   | Measurands.....  | 49        |

|           |   |           |
|-----------|---|-----------|
| 14.2      | Techniques.....   | 49        |
| 14.2.1    | Measurement of specific heat capacity.....  | 49        |
| 14.2.2    | Scanning thermal microscopy.....  | 49        |
| 14.3      | Relevant standard.....  | 50        |
| <b>15</b> | <b>Other performance related measurands.....</b>  | <b>50</b> |
| 15.1      | General.....  | 50        |
| 15.2      | Powders — Dustiness.....  | 50        |
| 15.2.1    | Measurands.....   | 50        |
| 15.2.2    | Relevant standards.....   | 50        |
| 15.3      | Liquid dispersions.....   | 51        |
| 15.3.1    | Measurands.....   | 51        |
| 15.3.2    | Viscosity.....  | 51        |
| 15.3.3    | Dispersibility.....   | 53        |
| 15.3.4    | Relevant standard.....  | 53        |
| 15.3.5    | Solubility and rate of dissolution.....   | 53        |
| 15.3.6    | Relevant standards.....   | 54        |
| 15.4      | Mechanical properties.....  | 54        |
| 15.4.1    | General.....  | 54        |
| 15.4.2    | Measurement of elastic constants by static methods.....                                   | 55        |
| 15.4.3    | Relevant standards.....   | 55        |
| 15.4.4    | Measurement of elastic constants by dynamic methods.....                                  | 55        |
| 15.4.5    | Relevant standards.....   | 56        |
| 15.4.6    | Measurement of elastic and plastic properties by instrumented indentation<br>methods..... | 56        |
| 15.4.7    | Relevant standards.....   | 56        |
| 15.4.8    | Measurement of surface properties and wear.....   | 56        |
| 15.4.9    | Relevant standard.....  | 57        |
|           | <b>Bibliography.....</b>  | <b>58</b> |